

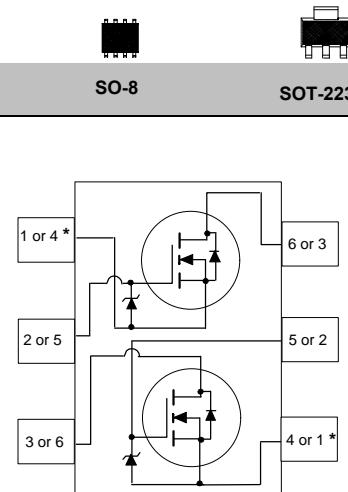
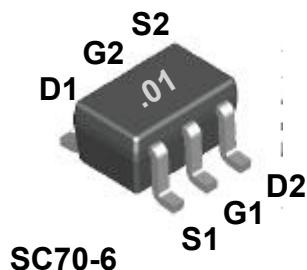
FDG6301N Dual N-Channel, Digital FET

General Description

These dual N-Channel logic level enhancement mode field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. This device has been designed especially for low voltage applications as a replacement for bipolar digital transistors and small signal MOSFETs.

Features

- 25 V, 0.22 A continuous, 0.65 A peak.
- $R_{DS(ON)} = 4 \Omega$ @ $V_{GS} = 4.5$ V,
 $R_{DS(ON)} = 5 \Omega$ @ $V_{GS} = 2.7$ V.
- Very low level gate drive requirements allowing direct operation in 3 V circuits ($V_{GS(th)} < 1.5$ V).
- Gate-Source Zener for ESD ruggedness (>6kV Human Body Model).
- Compact industry standard SC70-6 surface mount package.



* The pinouts are symmetrical; pin 1 and 4 are interchangeable.
 Units inside the carrier can be of either orientation and will not affect the functionality of the device.

Absolute Maximum Ratings $T_A = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	FDG6301N	Units
V_{DSS}	Drain-Source Voltage	25	V
V_{GSS}	Gate-Source Voltage	8	V
I_D	Drain/Output Current - Continuous	0.22	A
	- Pulsed	0.65	
P_D	Maximum Power Dissipation (Note 1)	0.3	W
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to 150	°C
ESD	Electrostatic Discharge Rating MIL-STD-883D Human Body Model(100 pF / 1500 Ω)	6.0	kV
THERMAL CHARACTERISTICS			
R_{QJA}	Thermal Resistance, Junction-to-Ambient	415	°C/W

Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
OFF CHARACTERISTICS						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}$, $I_D = 250\text{ }\mu\text{A}$	25			V
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	$I_D = 250\text{ }\mu\text{A}$, Referenced to 25°C		25		$\text{mV }/^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 20\text{ V}$, $V_{GS} = 0\text{ V}$ $T_J = 55^\circ\text{C}$		1	10	μA
I_{GSS}	Gate - Body Leakage Current	$V_{GS} = 8\text{ V}$, $V_{DS} = 0\text{ V}$			100	nA
ON CHARACTERISTICS (Note 2)						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$	0.65	0.85	1.5	V
$\Delta V_{GS(\text{th})}/\Delta T_J$	Gate Threshold Voltage Temp. Coefficient	$I_D = 250\text{ }\mu\text{A}$, Referenced to 25°C		-2.1		$\text{mV }/^\circ\text{C}$
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS} = 4.5\text{ V}$, $I_D = 0.22\text{ A}$ $T_J = 125^\circ\text{C}$	2.6	4		Ω
		$V_{GS} = 2.7\text{ V}$, $I_D = 0.19\text{ A}$	5.3	7		
$I_{D(\text{ON})}$	On-State Drain Current	$V_{GS} = 4.5\text{ V}$, $V_{DS} = 5\text{ V}$	0.22			A
g_{FS}	Forward Transconductance	$V_{DS} = 5\text{ V}$, $I_D = 0.22\text{ A}$		0.2		S
DYNAMIC CHARACTERISTICS						
C_{iss}	Input Capacitance	$V_{DS} = 10\text{ V}$, $V_{GS} = 0\text{ V}$, $f = 1.0\text{ MHz}$		9.5		pF
C_{oss}	Output Capacitance			6		pF
C_{rss}	Reverse Transfer Capacitance			1.3		pF
SWITCHING CHARACTERISTICS (Note 2)						
$t_{D(\text{on})}$	Turn - On Delay Time	$V_{DD} = 5\text{ V}$, $I_D = 0.5\text{ A}$, $V_{GS} = 4.5\text{ V}$, $R_{\text{GEN}} = 50\Omega$		5	10	ns
t_r	Turn - On Rise Time			4.5	10	ns
$t_{D(\text{off})}$	Turn - Off Delay Time			4	8	ns
t_f	Turn - Off Fall Time			3.2	7	ns
Q_g	Total Gate Charge	$V_{DS} = 5\text{ V}$, $I_D = 0.22\text{ A}$, $V_{GS} = 4.5\text{ V}$		0.29	0.4	nC
Q_{gs}	Gate-Source Charge			0.12		nC
Q_{gd}	Gate-Drain Charge			0.03		nC
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS						
I_s	Maximum Continuous Source Current				0.25	A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{ V}$, $I_s = 0.25\text{ A}$ (Note 2)		0.8	1.2	V

Notes:

- R_{ja} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{ja} is guaranteed by design while R_{jc} is determined by the user's board design. $R_{\text{ja}} = 415^\circ\text{C}/\text{W}$ on minimum pad mounting on FR-4 board in still air.
- Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2.0\%$.

Typical Electrical Characteristics

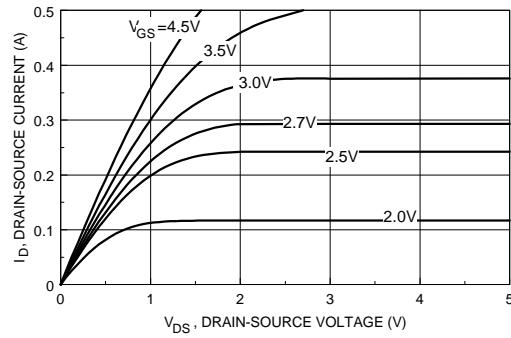


Figure 1. On-Region Characteristics.

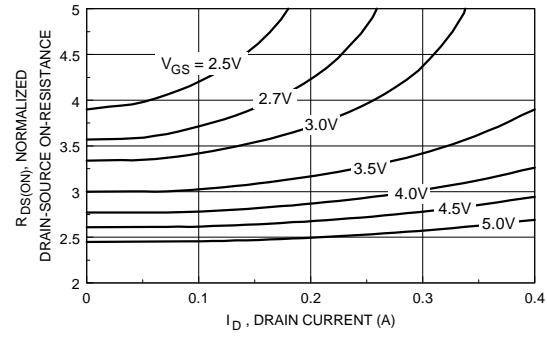


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

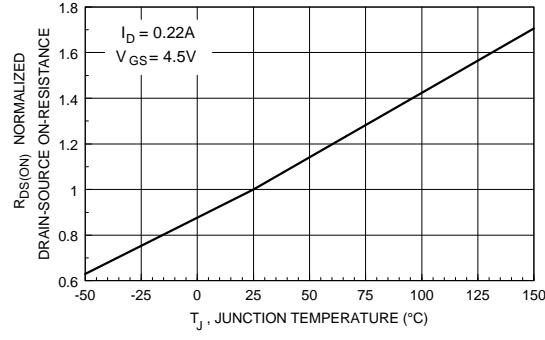


Figure 3. On-Resistance Variation with Temperature.

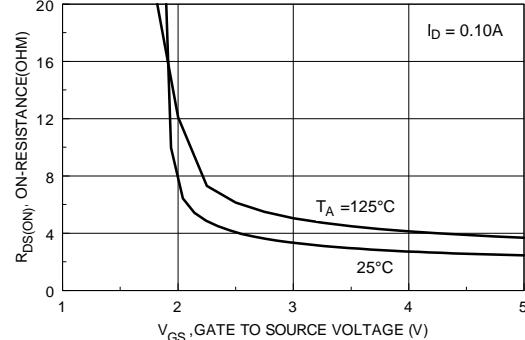


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

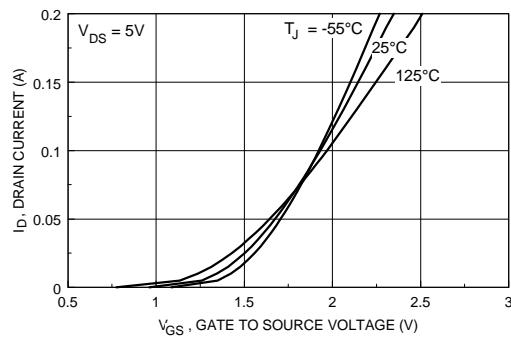


Figure 5. Transfer Characteristics.

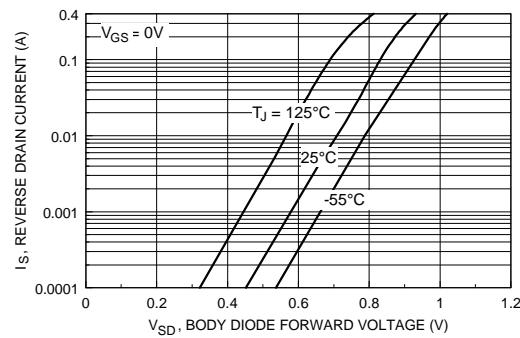


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Electrical Characteristics (continued)

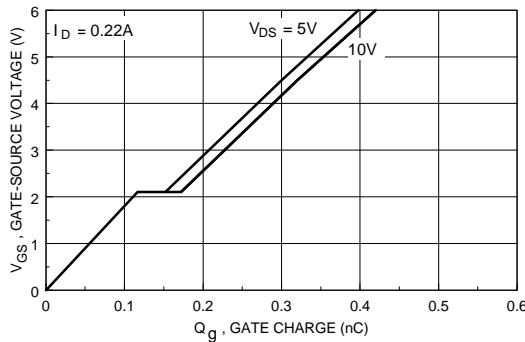


Figure 7. Gate Charge Characteristics.

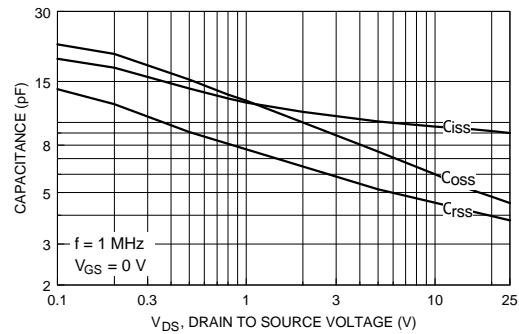


Figure 8. Capacitance Characteristics.

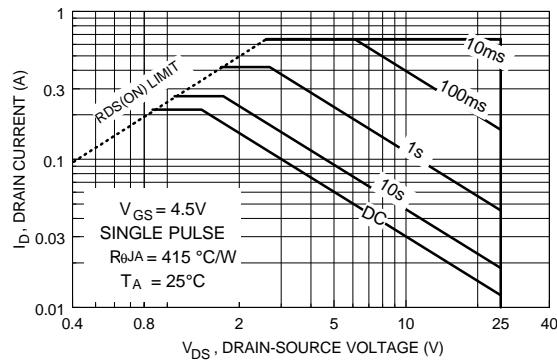


Figure 9. Maximum Safe Operating Area.

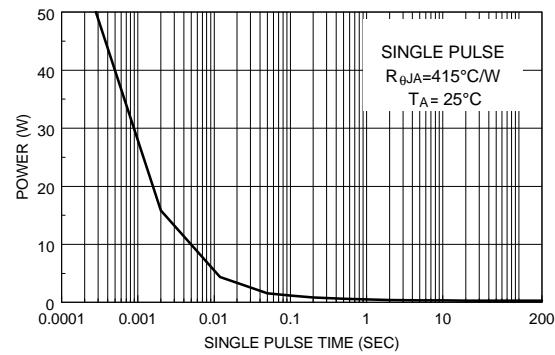


Figure 10. Single Pulse Maximum Power Dissipation.

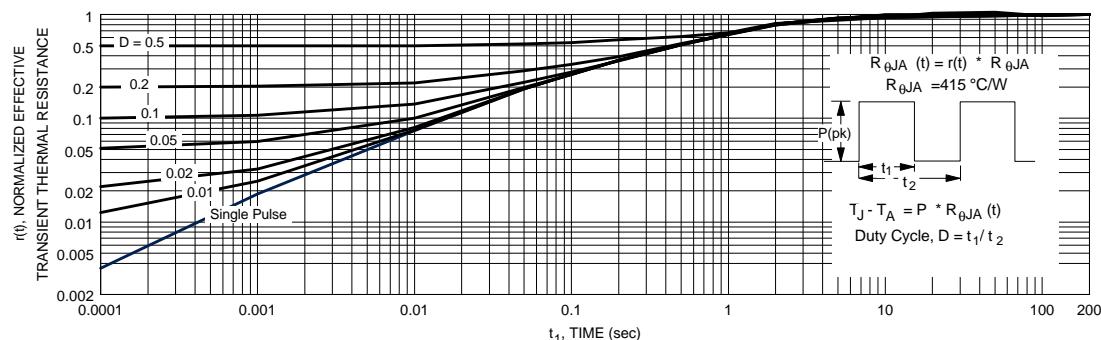


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in note 1.
Transient thermal response will change depending on the circuit board design.

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